

$$C_{\text{Int}}^{\pi \text{ MC}}(E_i) = \frac{N_{\text{Int}}^{\pi \text{ MC}}(E_i)}{N_{\text{Int}}^{\text{TOT MC}}(E_i)} \quad (1)$$

$$= \frac{N_{\text{Int}}^{\text{TOT MC}}(E_i) - B_{\text{Int}}^{\text{TOT MC}}(E_i)}{N_{\text{Int}}^{\text{TOT MC}}(E_i)} \quad (2)$$

$$C_{\text{Inc}}^{\pi \text{ MC}}(E_i) = \frac{N_{\text{Inc}}^{\pi \text{ MC}}(E_i)}{N_{\text{Inc}}^{\text{TOT MC}}(E_i)} \quad (3)$$

$$= \frac{N_{\text{Inc}}^{\text{TOT MC}}(E_i) - B_{\text{Inc}}^{\text{TOT MC}}(E_i)}{N_{\text{Inc}}^{\text{TOT MC}}(E_i)} \quad (4)$$

$$E_{\text{Front Face}}^{\text{kin}} = \sqrt{p_{\text{Beam}}^2 + m_{\text{Beam}}^2} - m_{\text{Beam}} - E_{\text{Loss}} \quad (5)$$

$$U_{i,j}^{\text{Int}}(E_i) \quad (6)$$

$$U_{i,j}^{\text{Inc}}(E_i) \quad (7)$$

$$E_j^{\text{kin}} = E_{\text{Front Face}}^{\text{kin}} - \sum_{j < i} E_{\text{dep } i} \quad (8)$$

$$E_i = \sqrt{p_{\text{Beam}}^2 + m_{\text{Beam}}^2} - m_{\text{Beam}} - E_{\text{Loss}} - E_{\text{dep FF-j}} \quad (9)$$

$$E_{\text{slice } j} = \sqrt{p_{\text{Beam}}^2 + m_{\text{Beam}}^2} - m_{\text{Beam}} - E_{\text{Loss}} - E_{\text{dep FF-j}} \quad (10)$$

$$\delta E_{\text{slice } j} = \sqrt{\delta p_{\text{Beam}}^2 + \delta E_{\text{Loss}}^2 + \delta E_{\text{dep FF-j}}^2} \quad (11)$$

	Low E Beam	High E Beam
G4Pions	70.9 %	82.3 %
G4Muons	14.6 %	13.5 %
G4Electrons	14.5 %	4.2 %

Table 1: Simulated beamline composition per magnet settings

$$E_{\text{dep FF-j}} = \sum_{j < s} E_{\text{dep s}} \Rightarrow \delta E_{\text{dep FF-j}} = (j - 1) \delta E_{\text{dep s}} \quad (12)$$

$$\sigma_{TOT}^{\pi^-}(E_i) = \frac{1}{n} \frac{\epsilon^{\text{Inc}}(E_i)}{\delta X} \frac{C_{\text{Int}}^{\pi MC}(E_i)}{\epsilon^{\text{Int}}(E_i)} \frac{N_{\text{Int}}^{\text{TOT}}(E_i)}{C_{\text{Inc}}^{\pi MC}(E_i)} \frac{N_{\text{Inc}}^{\text{TOT}}(E_i)}{N_{\text{Inc}}^{\text{TOT}}(E_i)}. \quad (13)$$

$$\sigma_{TOT}^{K^+}(E_i) = \frac{1}{n} \frac{\epsilon^{\text{Inc}}(E_i)}{\delta X} \frac{C_{\text{Int}}^{K MC}(E_i)}{\epsilon^{\text{Int}}(E_i)} \frac{N_{\text{Int}}^{\text{TOT}}(E_i)}{C_{\text{Inc}}^{K MC}(E_i)} \frac{N_{\text{Inc}}^{\text{TOT}}(E_i)}{N_{\text{Inc}}^{\text{TOT}}(E_i)}. \quad (14)$$

$$P_{\text{Int}} = \frac{N_{\text{Int}}}{N_{\text{Inc}}} = 1 - e^{-\sigma_{\text{TOT}} n \delta X} \quad (15)$$

$$\sigma_{\text{TOT}}(E) \sim \frac{1}{n} \frac{\delta X}{\delta X} \frac{N_{\text{Int}}}{N_{\text{Inc}}} \quad (16)$$

$$\sigma_{\text{TOT}}(E_i) = \frac{1}{n} \frac{\delta X}{\delta X} \frac{N_{\text{Int}}^{\pi^-}(E_i)}{N_{\text{Inc}}^{\pi^-}(E_i)} \quad (17)$$

$$\mathcal{L}(\mu_0; \sigma_0^2; \Delta\theta_0, \Delta\theta_1) = \prod_{i=0}^1 f_X(\Delta\theta_i, \mu_0, \sigma_0^2) \Rightarrow \quad (18)$$

$$\log \mathcal{L} = -\frac{1}{2} \log(2\pi) - \log \sigma_0 - \frac{1}{2} \frac{(\Delta\theta_0 - \mu_0)^2}{\sigma_0^2} + \text{same for } \Delta\theta_1 \quad (19)$$

	Run-II Neg Pol
1. Events Reconstructed in Beamline	158396
2. Events with Plausible Trajectory	147468
3. Beamline $\pi^-/\mu^-/e^-$ Candidate	138481
4. Events Surviving Pile Up Filter	108929
5. Events with WC2TPC Match	41757
6. Events Surviving Shower Filter	40841
7. Available Events For Cross Section	40841

Table 2: Number of data events for Run-II Negative and Positive polarity